

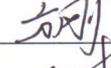
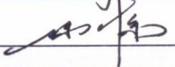


Test Report issued under the responsibility of:



<b>TEST REPORT</b> <b>IEC 60269-4</b> <b>Low-voltage fuses</b> <b>Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices</b>	
Report Number.....:	03601-A-23CB0182-S
Date of issue.....:	2024-04-25
Total number of pages.....:	29
Name of Testing Laboratory preparing the Report.....:	Suzhou Electrical Apparatus Science Research Institute Co., Ltd.(EETI)
Applicant's name.....:	Zhejiang Tengen Electric Co.,Ltd.
Address.....:	Sulv Industrial Area, Liushi Town, Yueqing City, Zhejiang Province, P.R.China
Test specification:	
Standard.....:	IEC 60269-4:2009, IEC 60269-4:2009/AMD1:2012, IEC 60269-4:2009/AMD2:2016 see also IEC 60269-1:2006, IEC 60269-1:2006/AMD1:2009, IEC 60269-1:2006/AMD2:2014
Test procedure.....:	CB Scheme
Non-standard test method.....:	N/A
TRF template used.....:	IECEE OD-2020-F1:2022, Ed.1.5
Test Report Form No. ....:	IEC60269_4D
Test Report Form(s) Originator .....	CQC
Master TRF.....:	Dated 2023-08-17
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<b>Test item description</b> .....	Fuse for the protection of semiconductor equipment	
<b>Trade Mark</b> .....	TENGEN	
<b>Manufacturer</b> .....	Zhejiang Tengen Electric Co.,Ltd. Sulv Industrial Area, Liushi Town, Yueqing City, Zhejiang Province, P.R.China	
<b>Model/Type reference</b> .....	TGRS3Z-5EP	
<b>Ratings</b> .....	See Page 6	
<b>Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):</b>		
<input checked="" type="checkbox"/>	<b>CB Testing Laboratory:</b>	Suzhou Electrical Apparatus Science Research Institute Co., Ltd.(EETI)
	<b>Testing location/ address</b> .....	No.7 Yonghe Street, Binhe Road, New District, Suzhou, China
	<b>Tested by (name, function, signature) .....</b>	Fang Gang (Team leader) 
	<b>Approved by (name, function, signature) ..</b>	Chen Yuan(Supervisor) 
<input type="checkbox"/>	<b>Testing procedure: CTF Stage 1:</b>	
	<b>Testing location/ address</b> .....	
	<b>Tested by (name, function, signature) .....</b>	
	<b>Approved by (name, function, signature) ..</b>	
<input type="checkbox"/>	<b>Testing procedure: CTF Stage 2:</b>	
	<b>Testing location/ address</b> .....	
	<b>Tested by (name + signature) .....</b>	
	<b>Witnessed by (name, function, signature) . :</b>	
	<b>Approved by (name, function, signature) .. :</b>	
<input type="checkbox"/>	<b>Testing procedure: CTF Stage 3:</b>	
<input type="checkbox"/>	<b>Testing procedure: CTF Stage 4:</b>	
	<b>Testing location/ address</b> .....	
	<b>Tested by (name, function, signature) .....</b>	
	<b>Witnessed by (name, function, signature) . :</b>	
	<b>Approved by (name, function, signature) .. :</b>	
	<b>Supervised by (name, function, signature) :</b>	

